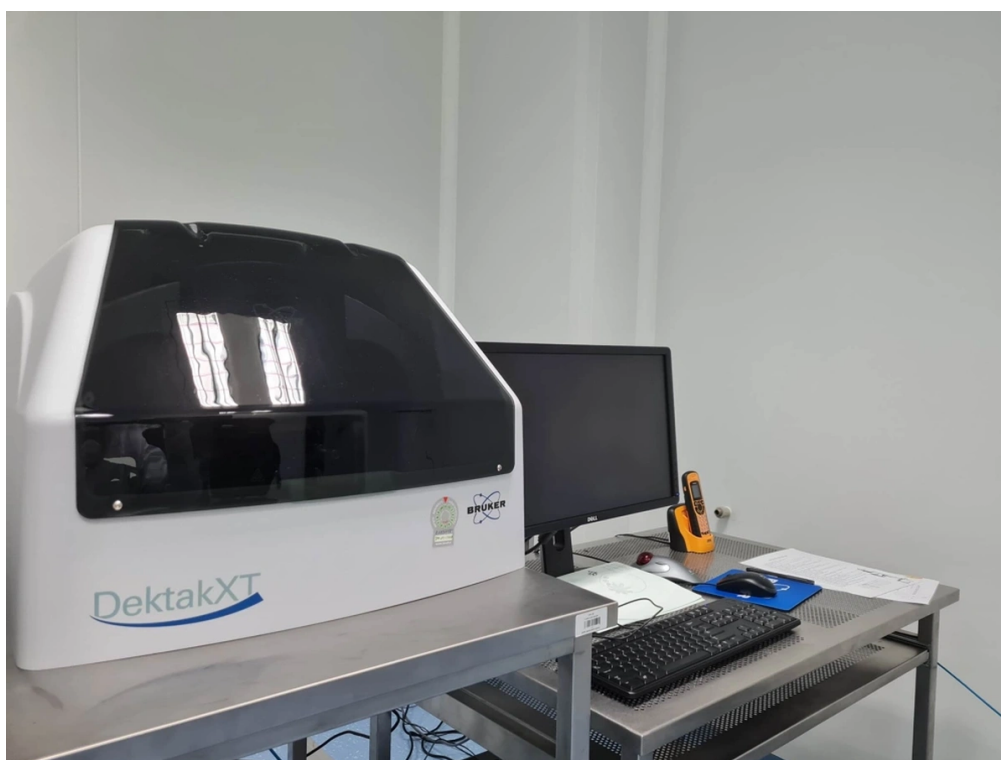


Profilometer for measuring nanometer-sized layers



Technical description:

Contact needle profilometer for testing surface roughness and waviness with a resolution of 1 Å and a repeatability of $4 \text{ Å} \leq$ (angstrom).

Trade name: Bruker DektakXT profilometer

More details: </equipment/profilometr-do-pomiarow-warstw-o-wymiarach-nanomet/>

Access type: External

Type of accreditation / certificate: Not applicable

Contact person: Jurzecka-Szymacha Maria

Contact person url: <https://skos.agh.edu.pl/osoba/maria-jurzecka-szymacha-7600.html>

Responsible body: Academic Centre for Materials and Nanotechnology

Group / laboratory / team: Department of Quantum Effects in Nanostructures

Last update date: Nov. 28, 2024, 2:44 p.m.

Year of commissioning: 2013

IDUB research areas:

(PRA 7) Design, production, and testing of modern materials and the technologies of the future based on a multidisciplinary approach combining materials engineering with chemistry, physics, mathematics, and medicine

Research capabilities:

The apparatus allows measuring the thickness of thin layers deposited by the user, creating profiles in specific directions, and exporting the values, along with roughness conversion.

Conditions for providing infrastructure:

Equipment is available in accordance with the Regulations for the Use of ACMiN's Research Infrastructure. (<https://acmin.agh.edu.pl/acmin/dokumenty/>)